

# Search Notes



Application/Control No.

10/085,145

Examiner

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Applicant(s)/Patent under Reexamination

MEISER ET AL.

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705	1	6/06	DN
	7		
	8		
	9		
	10		
	14		
	26		
709	202		
	205		
	217		
	229		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
US	6/06	DN
Pat		
PG Pub		
FOREIGN		
EPO		
JPO		
KNOW		